

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1295	702/182.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/02/13 13:41
L3	641	700/108.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/02/13 13:43
L6	6	(manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near\$4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments).clm.	US-PGPUB	OR	ON	2006/02/13 13:48
L7	1	3 and 6	US-PGPUB	OR	ON	2006/02/13 13:48
L8	2	2 and 6	US-PGPUB	OR	ON	2006/02/13 13:48
S1	3	manufactur\$4 and ((yield\$1 or production) with (loss or low) with time with period) and ((detect\$3 or identif\$4 or determin\$3 or monitor\$3) with (stability or fail\$3 or disorder or breakdown) with (machine\$1 or apparatus\$1 or instrument\$1 or press or device\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:51
S2	1314	(manufactur\$4 or fabricating) and ((yield\$1 or product\$5) with (loss or low or fail\$3) with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:08
S3	44	S2 and ((detect\$3 or identif\$4 or determin\$3 or monitor\$3 or inspect\$3) with (stability or fail\$3 or disorder or breakdown) with (machine\$1 or apparatus\$1 or instrument\$1 or press or device\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 16:20
S4	28831	((detect\$3 or identif\$4 or determin\$3 or monitor\$3 or inspect\$3 or examin\$3) with (stability or fail\$4 or fault\$1 or disorder or breakdown or disabl\$3 or quality or (low\$2 with yield\$1))) and ((machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with ((production adj line) or parallel))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:10
S5	37	S4 and S2	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 16:43
S6	513	(manufactur\$4 or fabricating or product\$3) and (yield\$1 with low\$2 with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:18

S7	31	(machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line) with parallel with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:13
S8	0	S6 and S7	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:11
S9	63531	(machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with parallel with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:12
S10	1	S6 and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:12
S11	606	(machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line) with plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:20
S12	1	S6 and S11	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:13
S13	529	(manufactur\$4 or fabricating or product\$3) and ((yield\$1 or (production adj rate\$1)) with low\$2 with time with period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:23
S14	12262	(machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with (production adj line)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:36
S15	9	S13 and S14	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:20
S16	107987	(manufactur\$4 or fabricating or product\$3) and ((yield\$1 or (production adj rate\$1)) with low\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:37
S17	224	S14 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:23

S18	0	S17 and (downward with tendency)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:27
S19	2335	(downward with tendency)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:24
S20	10	S14 and S19	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:25
S21	4	S17 and ((history or tendency or trend) with yield\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:37
S22	15320	(machine\$3 or apparatus\$1 or instrument\$1 or device\$1 or equipment\$1) with ((production or manufactur\$3) adj line)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:49
S23	319	S22 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:37
S24	13	S23 and ((history or tendency or trend) with yield\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 17:40
S25	1	S22 and (low adj yield adj period)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/12/18 19:22
S26	987	702/182.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:01
S27	2	"5274434".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/03 15:44
S28	2	"4357574".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/03 15:45

S29	3	"6611728".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:15
S30	2	"20020143483"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:16
S31	2	"20030176939"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/01/04 15:16
S32	136910	(production or manufactur\$3 or fabrication) and (semiconductor or semi adj conductor or wafer\$1) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1 or press or device\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:23
S33	1596	S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2 or decreas\$3 or increas\$3) with (time or period\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 13:43
S34	932	S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2) with (time or period\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 13:44
S35	72	S32 and ((yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1) with (loss or low\$2 or high\$2) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:25
S36	253190	(production or manufactur\$3 or fabrication) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:34
S37	214	S36 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2 or defect\$3 or fail\$3) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:35
S38	207097	(manufactur\$3 or fabrication) and (plurality or group) with (machine\$1 or apparatus or instrument\$1 or equipment\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:34
S39	174	S38 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2 or defect\$3 or fail\$3) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:36

S40	92	S38 and ((yield\$1 or production near4 rate\$1 or quality) with (loss or low\$2) with (time or period\$1)) with (detect\$3 or identif\$4 or determin\$3 or isolat\$3 or judg\$5 or establish\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/27 14:46
S41	37	(manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:56
S42	633	702/108.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:51
S43	342	356/237.4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:51
S44	37	(manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:02
S45	0	S42 and S44	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:57
S46	0	S43 and S44	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:57
S47	0	700/108.ccls	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:58
S48	592	700/108.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/02/13 13:43
S49	6	S44 and S48	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 13:59

S50	1202	702/182.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2006/02/13 13:41
S51	3	S44 and S50	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:01
S52	4	(manufactur\$3 or fabrication) same (detect\$3 or determin\$3 or identif\$4 or measur\$3 or judg\$5 or analy\$4 or diagnos\$3) with (degrad\$3 or abnormal\$5 or performance or yield\$1 or (production or defect\$3 or fail\$3) near\$4 rate\$1 or quality) with (period or time) same (plurality or group or multiple) with (apparatus or machin\$4 or equipments or instruments).clm.	US-PGPUB	OR	OFF	2006/02/13 13:40
S53	1	S50 and S52	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:03
S54	0	S47 and S52	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/09/30 14:03